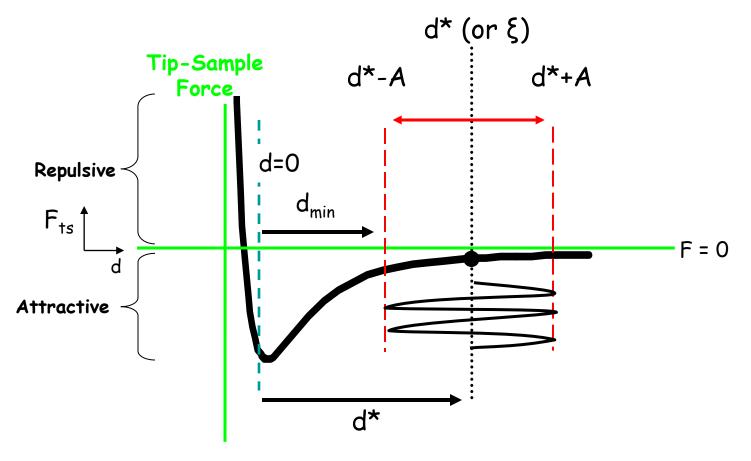
ME597/PHYS57000 Fall Semester 2009 Lecture 22

Frequency Modulated AFM - Experimental Details -

Suggested Reading: F. Giessibl, Rev. Mod. Phys. 75, 949 (2003)

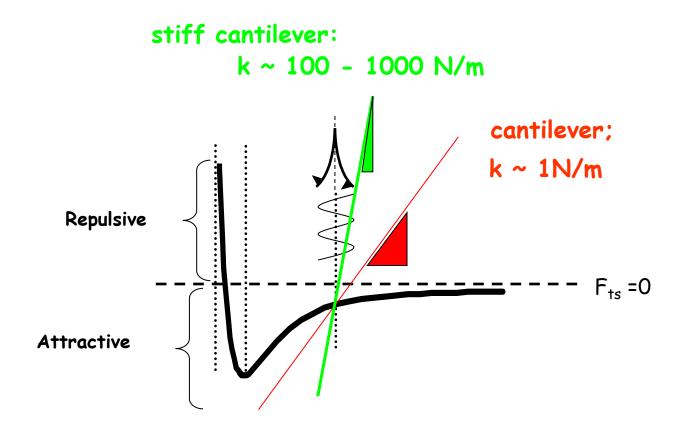
Last Lecture



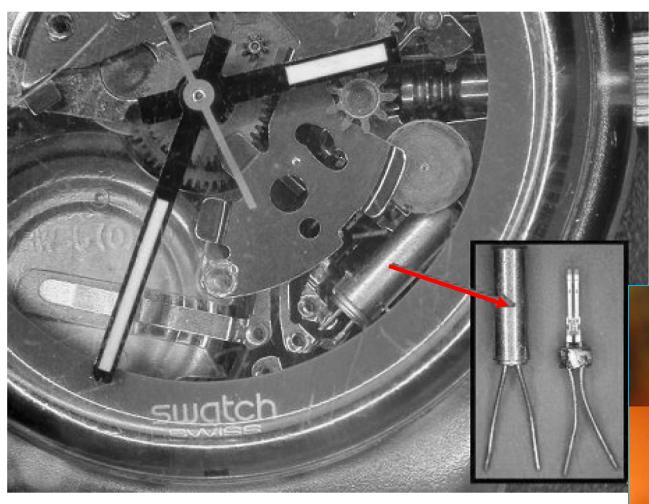
$$\begin{split} F_{ts}(d_{\min}) &= 2k_c \int_{d_{\min}}^{\infty} \left\{ \left[1 + \frac{\sqrt{A}}{8\sqrt{\pi(\xi - d_{\min})}} \right] \Omega(\xi) - \frac{A^{3/2}}{\sqrt{2 \xi - d_{\min}}} \frac{d\Omega(\xi)}{d\xi} \right\} d\xi \\ \text{where } \Omega(\xi) &\equiv \frac{\Delta f(\xi)}{f_o} \qquad \xi \Leftrightarrow d^* \end{split}$$

What is Required?

- High stability
- Must measure small frequency shifts accurately
- Large spring constant to eliminate jump to contact



New Idea: Tuning Forks



Bulova Accutron: 1960

Cost: ~0.25 USD

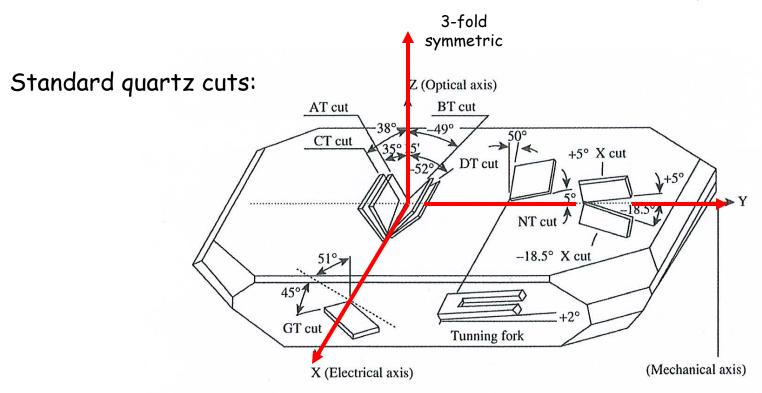


Source: wikipedia

 $f_o = 2^N$; N = integer $f_o = 2^{15} = 32,768.0000 \text{ Hz}$

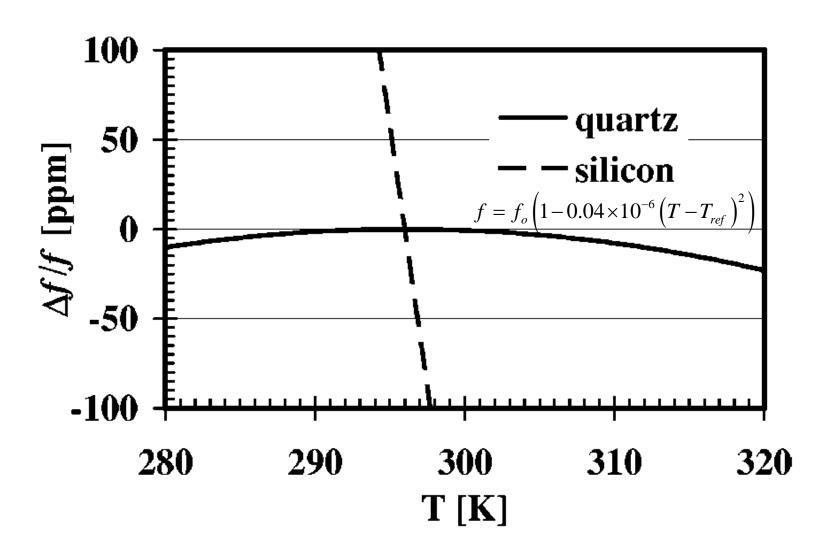
Quartz: a piezoelectric material

(highly anisotropic crystalline $SiO_{2)}$

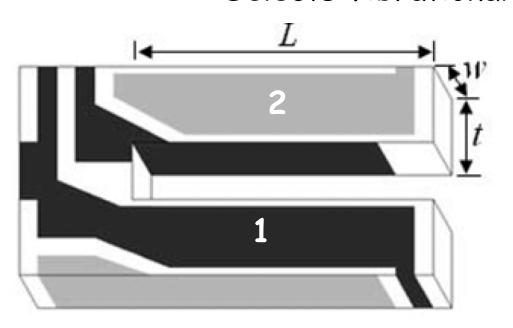


Mechanical stress develops electric potential

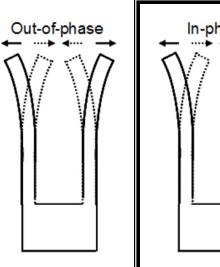
Thermal stability of quartz compared to Si

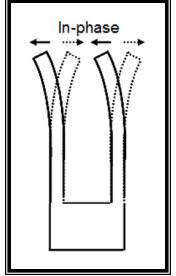


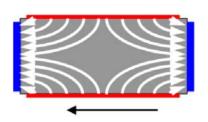
Electrode Geometry Selects Vibrational Mode

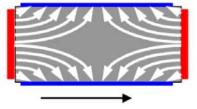


$$V_{12} = V_o \sin(\omega t)$$

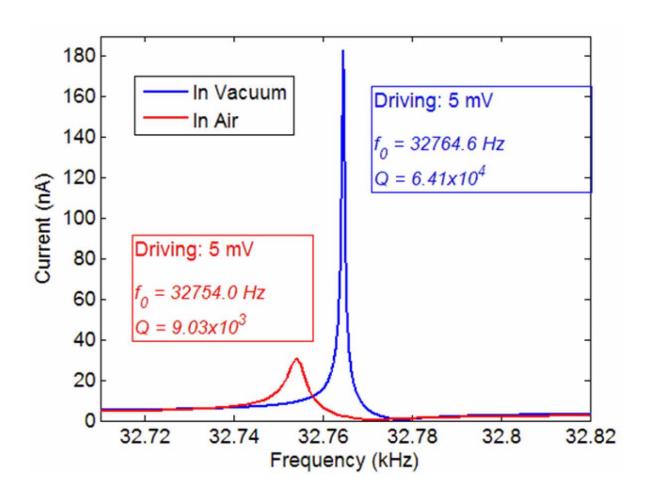




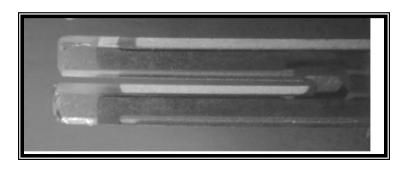




Vibration Spectrum

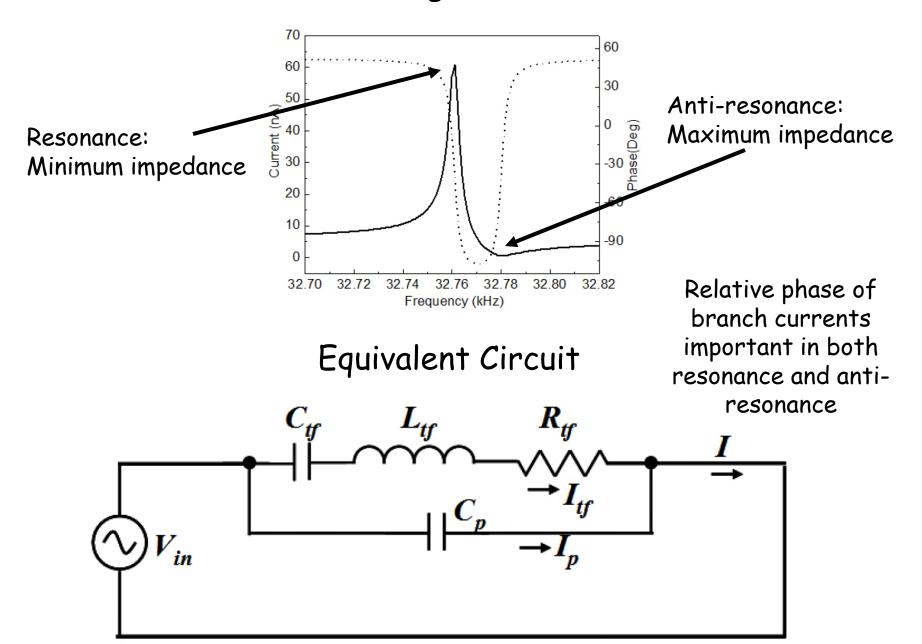


Raltron Model R26 Tuning Fork

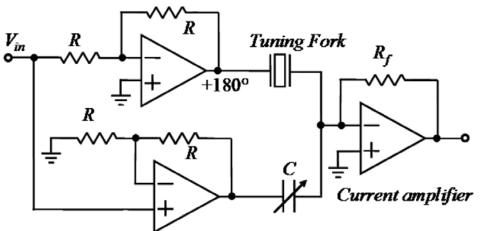


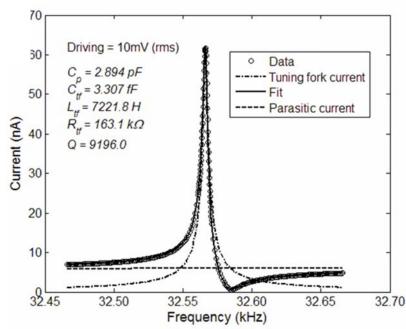
Length (mm)	3.20 ± 0.01	Effective mass (kg)	2.72×10^{-7}
Thickness (mm)	0.40 ± 0.01	Spring constant (kN/m)	12.7
Width (mm)	0.33 ± 0.01	Resonance (kHz)	34.39
Density (kg/m^3)	2.65×10^3	Young's Modulus(Pa)	7.87×10^{10}

Understanding the Resonance

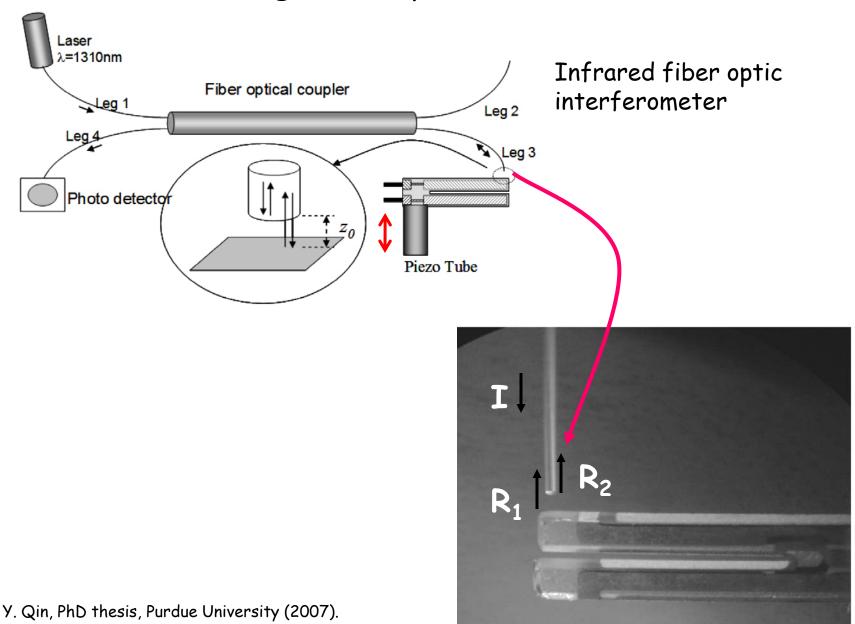


Eliminating the Parasitic Capacitance

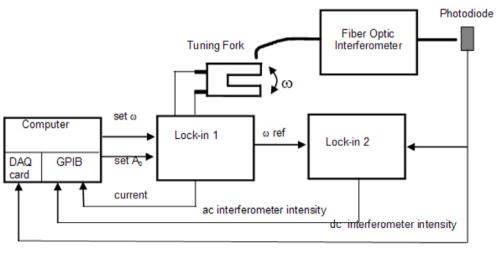


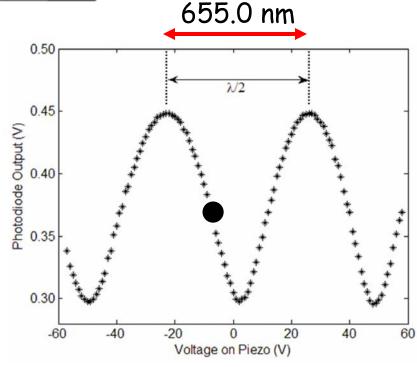


Calibrating the Amplitude of Oscillation



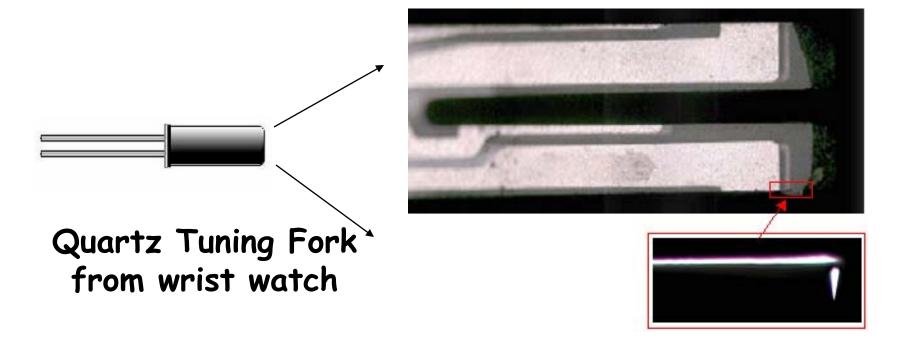
Typical calibration (determining A_o vs. applied driving voltage)





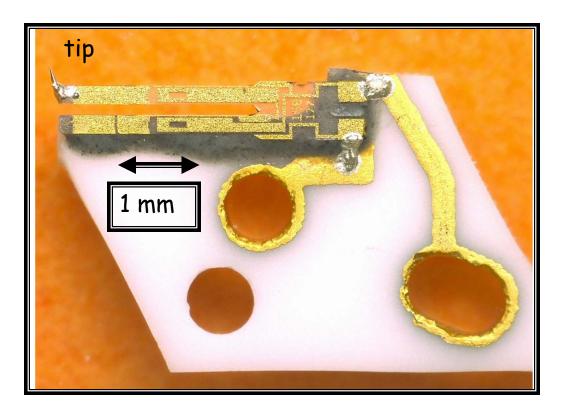
Mounting a Tip: Tuning Fork AFM

 $k \cong 1000 \text{ N/m}$



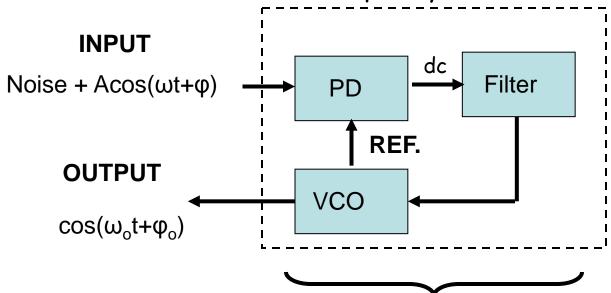
Q in vacuum $\approx 45,000$ Q in air $\approx 9,000$

Commercially available Q-plus sensor



Intro to Phase Locked Loops (PLLs)

Phase-Locked Loops (PLLs) track the frequency of an input "noisy" sinusoidal signal that is known to have a variable frequency.



The PLL consists of three components:

- Phase Detector (PD)
- Loop filter
- Voltage-Controlled Oscillator (VCO)

PLL Notes: PLL

It is assumed that the frequency change of the input signal is not too large.

It is assumed that the approximate frequency range of the input signal is roughly known.

The PD estimates the phase difference between an input (noisy) signal and a clean signal (reference) produced by the VCO. The PD circuit generates a <u>dc</u> voltage proportional to the phase difference between these two signals.

The loop filter "smoothes" the **dc** voltage produced by the PD.

The VCO accepts the smoothed <u>dc</u> voltage and generates a signal with a frequency that is continuously adjusted by the <u>dc</u> voltage. This is accomplished by modifying the frequency of an internal oscillator (no noise) until a match to the frequency of the input signal is achieved.

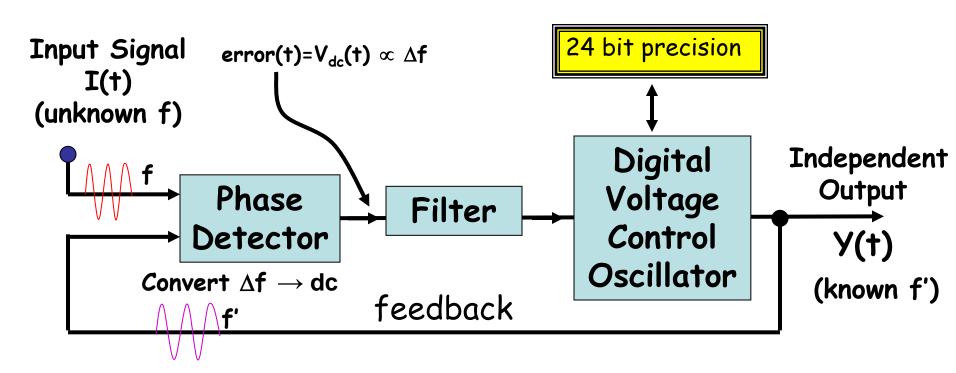
When a match occurs, the <u>dc</u> voltage produced by the filter goes to **zero** and the known output (ω_o, φ_o) is said to match the input (ω, φ) .

The PLL-design goal is to select an appropriate loop filter that produces an acceptable transient and steady-state response of the closed-loop system

The "bandwidth" of a PLL is the frequency at which the PLL begins to lose "lock" with the reference signal.

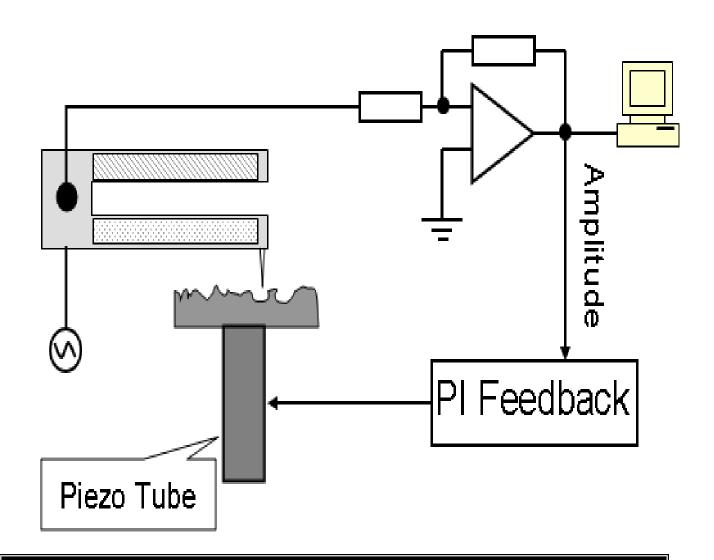
Principle of Digital Phase-Lock Loops (PLL)

TASK: Instantly track and measure frequency of an input signal I(t) with high accuracy



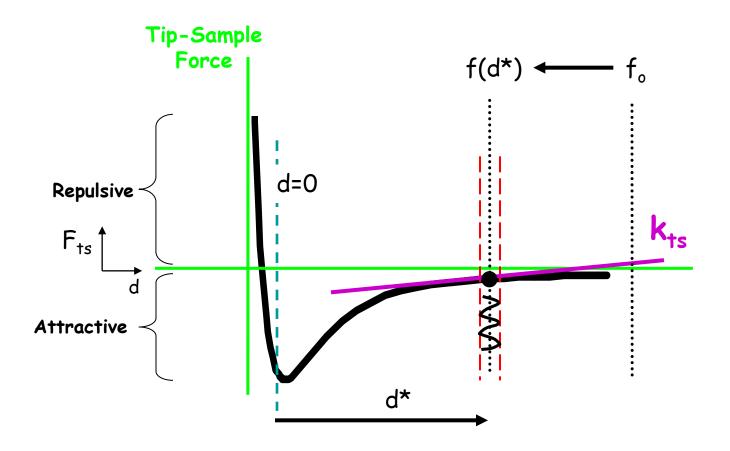
- · Negative feedback!
- Goal is to make $\Delta f = f f' = 0$

Tuning Fork AFM



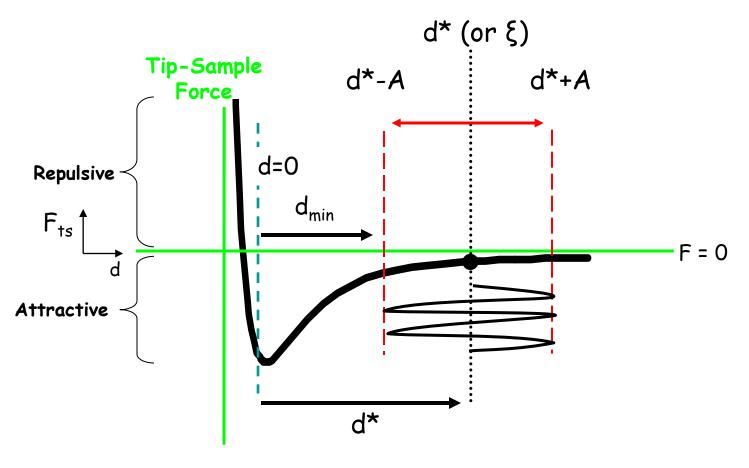
No laser required to measure deflection

FM-AFM Constant Frequency Images



Scan while keeping $w(d^*)$ and Q constant

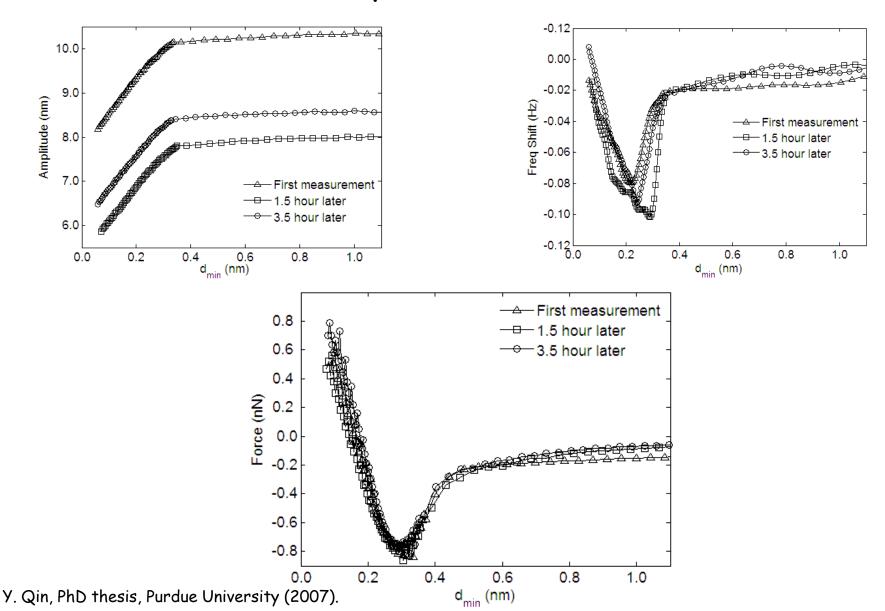
FM-AFM Force Spectroscopy



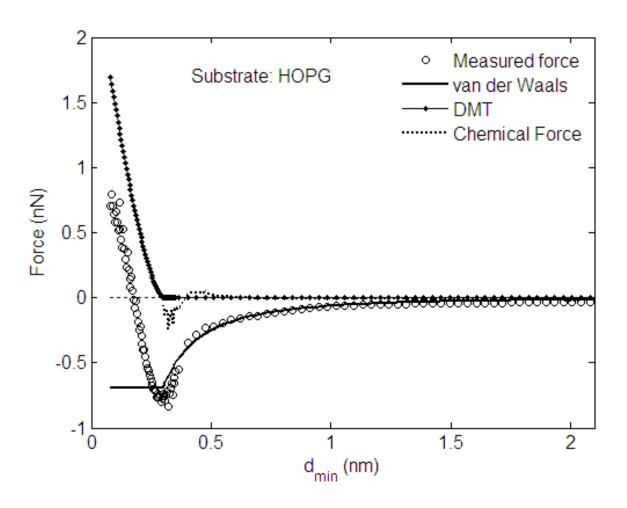
$$\begin{split} F_{ts}(d_{\min}) &= 2k_c \int_{d_{\min}}^{\infty} \left\{ \left[1 + \frac{\sqrt{A}}{8\sqrt{\pi(\xi - d_{\min})}} \right] \Omega(\xi) - \frac{A^{3/2}}{\sqrt{2 \xi - d_{\min}}} \frac{d\Omega(\xi)}{d\xi} \right\} d\xi \\ \text{where } \Omega(\xi) &\equiv \frac{\Delta f(\xi)}{f_o} \qquad \xi \Leftrightarrow d^* \end{split}$$

FM-AFM Force Spectroscopy

W tip - HOPG substrate



Fit to data



FIT: $a_0=0.3$ nm, H=3.3×10⁻¹⁹ J, E*=11.6 GPa, $R_{eff}=1.13$ nm

Y. Qin, PhD thesis, Purdue University (2007).